Application Note No. 024

Parasitic Capacitance in Bipolar Junction Transistors

RF & Protection Devices



Never stop thinking

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Parasitic Capacitance in Bipolar Junction Transistors

1 Parasitic Capacitance in Bipolar Junction Transistors

The parasitic capacitance present in any bipolar junction transistor can be best modeled as three capacitors connected between each of the three ports of the transistor.

Historically, a number of different capacitance characterizations have been used and published. This application note shows the most popular of these different definitions.

Definition





Measurement Related Definitions



Figure 2 $C_{\rm ibo}$ and $C_{\rm ibs}$ definition



Parasitic Capacitance in Bipolar Junction Transistors

Ceb



measurement bridge.

Figure 4 $C_{\rm re}$ and $C_{\rm rb}$ definition

Ccb

AN024_capacitance_Cre_Crb.vs



Parasitic Capacitance in Bipolar Junction Transistors

How to measure $C_{\rm cb}$, $C_{\rm ce}$ and $C_{\rm eb}$

For simple measurements, the features of a capacitance bridge (e.g. HP4279A) can be used. This type of bridge can measure capacitances between two coax outputs and ignore capacitances from coax output to ground. They can also apply DC voltages to the ports for biasing.

- To measure C_{cb} , ground emitter and measure between collector and base.
- To measure C_{ce} , ground base and measure between collector and emitter.
- To measure $C_{\rm eb}$, ground collector and measure between emitter and base.

The measurement strategy can be seen above in $C_{\rm re}$ and $C_{\rm rb}$ definition. When the third lead of the device is grounded, only the capacitance between the other two leads is measured.

Note: Some names of capacitances are used in industry with different meanings.